

**TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT**  
**(Under 37 CFR 1.97(b) or 1.97(c))**

Docket No.  
03100275AA

In Re Application Of: **B. Bodermann**

Application No.  
**10/564449**  
not yet assigned

Filing Date  
concurrently

Examiner  
not yet assigned

Customer No.  
30743

Group Art Unit  
not yet assigned

Confirmation No.  
not yet assigned

Title: **METHOD FOR DETERMINING THE REFRACTIVE INDEX DURING INTERFEROMETRIC LENGTH MEASUREMENT AND INTERFEROMETRIC ARRANGEMENT THEREFOR**

Address to:

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**37 CFR 1.97(b)**

1. ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.

**37 CFR 1.97(c)**

2. ☐ The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:

☐ the statement specified in 37 CFR 1.97(e);

**OR**
☐ the fee set forth in 37 CFR 1.17(p).

1AP20 REGISTRATION 12 JAN 2006

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(Under 37 CFR 1.97(b) or 1.97(c))

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Title: **METHOD FOR DETERMINING THE REFRACTIVE INDEX DURING INTERFEROMETRIC LENGTH MEASUREMENT AND INTERFEROMETRIC ARRANGEMENT THEREFOR**

**Payment of Fee**

(Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p))

- ☐ A check in the amount of \_\_\_\_\_ is attached.
- ☒ The Director is hereby authorized to charge and credit Deposit Account No. 50-2041 as described below.
- ☐ Charge the amount of \_\_\_\_\_
- ☒ Credit any overpayment.
- ☒ Charge any additional fee required.
- ☐ Payment by credit card. Form PTO-2038 is attached.

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I certify that this document and authorization to charge deposit account is being facsimile transmitted to the United States Patent and Trademark Office (Fa

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(Date)

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Signature

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Typed or Printed Name of Person Signing Certificate

**Certificate of Mailing by First Class Mail**

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450" [37 CFR 1.8(a)] on

\_\_\_\_\_  
(Date)

\_\_\_\_\_  
Signature of Person Mailing Correspondence

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Typed or Printed Name of Person Mailing Certificate

**\*This certificate may only be used if paying by deposit account.**

  
Signature

Dated: January 12, 2006

Marshall M. Curtis  
Reg. No. 33,138  
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11491 Sunset Hills Road, Suite 340  
Reston, Virginia 20190  
703-787-9400  
CUSTOMER NUMBER 30743

cc:

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

10/564449 22 JAN 2006

B. Bodermann

Serial No.: not yet assigned

Examiner: not yet assigned

Filing Date: Concurrently

Group Art Unit: not yet assigned

For: METHOD FOR DETERMINING THE REFRACTIVE INDEX  
DURING INTERFEROMETRIC LENGTH MEASUREMENT  
AND INTERFEROMETRIC ARRANGEMENT THEREFOR

Commissioner for Patents  
PO Box 1450  
Alexandria, Virginia 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Sir:

Under the provisions of 37 C.F.R. 1.97 through 1.99 and pursuant to applicant's duty of disclosure under 37 C.F.R. 1.56, applicant respectfully brings the following documents, listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application.

These citations do not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application. Please charge any deficiencies in fees and credit any overpayment of fees to attorney's Deposit Account No. 50-2041.

Respectfully submitted,



Marshall M. Curtis

Registration No.: 33,138

703-787-9400

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11491 Sunset Hills Road, Suite 340  
Reston, Virginia 20190

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**Customer No. 30743**

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO.		APPLICATION NO.	
				03100275AA		<b>10/564479</b> not yet assigned	
				APPLICANT(S)		FILING DATE	
				B. Bodermann		12 JAN 2006	
				concurrently		GROUP ART UNIT not yet assigned	

  

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6417927	7/2002	de Groot			
		3877813	4/1975	Hayes et al.			
		5838485	11/1998	de Groot et al.			
		5764362	6/1998	Hill et al.			
		5404222	4/1995	Lis			

  

U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/0001086	1/2002	De Groot			

  

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
		2346967	8/2000	United Kingdom			✓	
		19727402	2/1998	Germany				✓
		19727404	2/1998	Germany				✓
		WO99/42787	8/1999	International			✓	

  

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			
			G. Bonsch et al., "Measurement of the Refractive Index of Air and Comparison with Modified Edlen's Formulae"; Metrologia, 1998 Vol. 35, PP 133-139.
			B. Boermann et al., "Improved Second Harmonic Two Wavelength Interferometer with Refractive Index Correction without Effect Modulation"; Proc. of SPIE, Vol. 5190, 2003; pp. 339-346.

  

<b>EXAMINER</b>	<b>DATE CONSIDERED</b>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. <b>03100275AA</b>		APPLICATION NO. <b>10/564449</b> not yet assigned			
				B. Bodermann				12 JAN 2006	
				FILING concurrently		GROUP ART not yet assigned			

  

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		4948254	8/1990	Ishida			
		6014216	1/2000	Zorabedian			
		5412474	5/1995	Reasenberget al.			

  

U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

  

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

  

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			

  

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